### **BiTS 2017**

## **Poster Session**



Burn-in & Test Strategies Workshop

www.bitsworkshop.org

March 5-8, 2017

## **BiTS 2017**

# **Copyright Notice**

The presentation(s)/poster(s) in this publication comprise the Proceedings of the 2017 BiTS Workshop. The content reflects the opinion of the authors and their respective companies. They are reproduced here as they were presented at the 2017 BiTS Workshop. This version of the presentation or poster may differ from the version that was distributed in hardcopy & softcopy form at the 2017 BiTS Workshop. The inclusion of the presentations/posters in this publication does not constitute an endorsement by BiTS Workshop or the workshop's sponsors.

There is NO copyright protection claimed on the presentation/poster content by BiTS Workshop. However, each presentation/poster is the work of the authors and their respective companies: as such, it is strongly encouraged that any use reflect proper acknowledgement to the appropriate source. Any questions regarding the use of any materials presented should be directed to the author(s) or their companies.

The BiTS logo and 'Burn-in & Test Strategies Workshop' are trademarks of BiTS Workshop. All rights reserved.



## **BiTS 2017**

## **Poster Session**





### Universal Adjustable Docking for Automated Test Equipment Systems

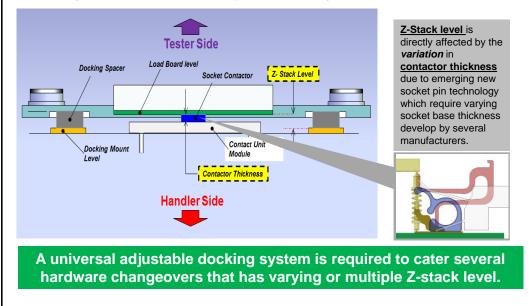
Jess Coleta , Willy Ganoy On Semiconductor Philippines

**Docking System** is a very critical hardware component used to interface on automated test equipment(ATE) and automated placement tool(Handler) that help improve the repeatability of test setup and flexibility to adapt from a full range of ATE to Handler Tandem available in the market.

This topic explains the new techniques in designing/modifying a new and old Docking System that is cost effective but yet mechanically robust and flexible.

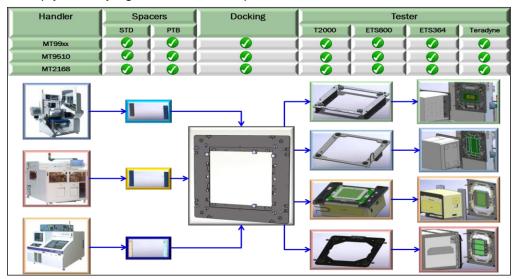
#### Motivation

Due to increase of number of hardware interfacing set ups required for newly developed devices requiring new contacting technology solution that affects the Z-stack docking level which makes the docking system nowadays to become more complex and costly as well.



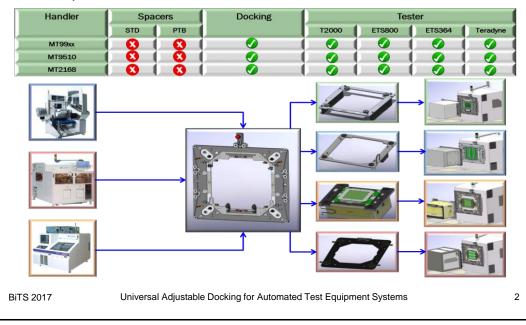
### **Basic Design Practices**

Current approach in developing new docking system are mostly dedicated to handler which requires **specific docking spacers or indexer plates** to comply on varying Z-stack level requirements.



### **New Design Techniques**

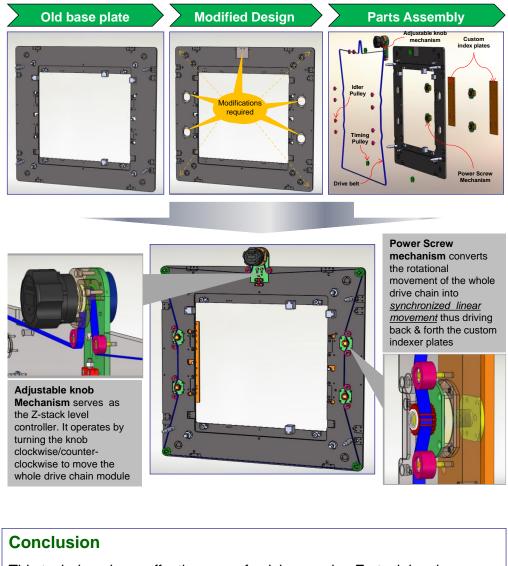
The solution is to eliminate the use of dedicated spacers by integrating a *power screw mechanism* which can be adjusted and will drive back & forth the custom handler mount plate to comply on the varying Z-stack level requirements. In reference to US Patent# : 9519023



Burn-in & Test Strategies Workshop www.bitsworkshop.org

### **Adapting Design Concepts**

Fabricating the whole docking system to comply on a new ATE and handler interface which require new Z-stack level is very costly. Other approach is to integrate this new design concept on your existing docking hardware to save cost.



This technique is an effective way of solving varying Z-stack level requirements & interchanging setups caused by emerging contacting technology and various range of ATE systems/handlers tandem available in the market.

BiTS 2017

Universal Adjustable Docking for Automated Test Equipment Systems

3